350.00 MHz One Port SAW Resonator

- ***Ideal for 350.00 MHz Transmitters***
- ***Very Low Insertion Loss***
- ***Quartz Stability***
- ***Ultra Miniature Ceramic SMD Package (QCC8C)***

Absolute Maximum Rating (Ta=25qC)			
Parameter		Rating	Unit
CW RF Power Dissipation	*P*	0	dBm
DC Voltage	V_{DC}	r 30	V
Operating Temperature Range	T_A	-10 ~ +60	qC
Storage Temperature Range	T_{stg}	-40 ~ +85	qC

Electronic Characteristics						
Parameter		Sym	Minimum	Typical	Maximum	Unit
Frequency (25qC)	Nominal Frequency	f_c	NS	350.00	NS	MHz
	Tolerance from 350.00 MHz	$'f_c$	-	-	r 75	KHz
Insertion Loss		*IL*	-	1.5	2.2	dB
Quality Factor	Unloaded Q-Value	Q_u	-	10,650	-	-
	50: Loaded Q-Value	Q_L	-	1,700	-	-
Temperature Stability	Turnover Temperature	T_o	25	-	55	qC
	Turnover Frequency	f_o	-	f_c	-	KHz
	Frequency Temperature Coefficient	*FTC*	-	0.032	-	ppm/qC^2
Frequency Aging	Absolute Value during the First Year	$\|f_A\|$	-	-	10	ppm/yr
DC Insulation Resistance Between any Two Pins		-	1.0	-	-	M:
RF Equivalent RLC Model	Motional Resistance	R_M	-	19	29	:
	Motional Inductance	L_M	-	92.0382	-	PH
	Motional Capacitance	C_M	-	2.2489	-	fF
	Shunt Static Capacitance	C_o	2.4	2.7	3.0	pF

NS = Not Specified

Note:

1. The frequency f_c is the frequency of minimum IL with the resonator in the specified test fixture in a 50: test system with VSWR d 1.2:1.
2. Unless noted otherwise, case temperature TC = +25°C±2°C.
3. Frequency aging is the change in fC with time and is specified at +65°C or less. Aging may exceed the specification for prolonged temperatures above +65°C. Typically, aging is greatest the first year after manufacture, decreasing in subsequent years.
4. Turnover temperature, T0, is the temperature of maximum (or turnover) frequency, f0. The nominal frequency at any case temperature, TC, may be calculated from: f = f_o [1 - *FTC* (T_O - T_C)^2].
5. This equivalent RLC model approximates resonator performance near the resonant frequency and is provided for reference only. The capacitance C_O is the measured static (nonmotional) capacitance between input terminal and ground or output terminal and ground. The measurement includes case parasitic capacitance.
6. Derived mathematically from one or more of the following directly measured parameters: f_c, *IL*

Phone: +86 10 6301 4184 Fax: +86 10 6301 9167 Email: sales@vanlong.com Web: http://www.vanlong.com

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